

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Art Unit

2811

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Taek Kim et al., "Cr/Ni/Au ohmic contacts to the moderately doped p- and n-GaN" Mat. Res. Soc. Symp. Proc. Vol. 449, 1997, pp 1061-1065.
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